TOSHIBA Bipolar Linear Integrated Circuit Silicon Monolithic

TA8552AFN

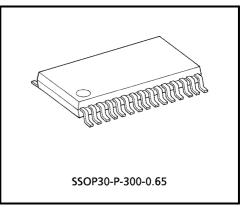
PLL Data Synchronizer For DAT Streamer

The TA8552AFN is PLL data synchronizer for digital audio tape (DAT) strteamer, digital data storage (DDS).

Features

- The TA8552AFN incorporates edge detector, data synchronizer, and latch for data separator.
 Also the TA8552AFN is available to correspond to ×1, ×2 and ×3 of data transfer rates by adjusting external devices.
- The data synchronizer is avalable to correspond to $\pm 7\%$ variation of data transfer rate.
- By employing full differential signal processing in PLL loop, the TA8552AFN eliminates the influence of external noise. Fast & stable locking is realized by switching between the frequency detective mode and the phase detective mode.
- Operating power supply voltage range: 4.5V to 5.5V
- Small package; SSOP30-P-300-0.65

Handle with care to prevent devices from deterioration by static electricity.



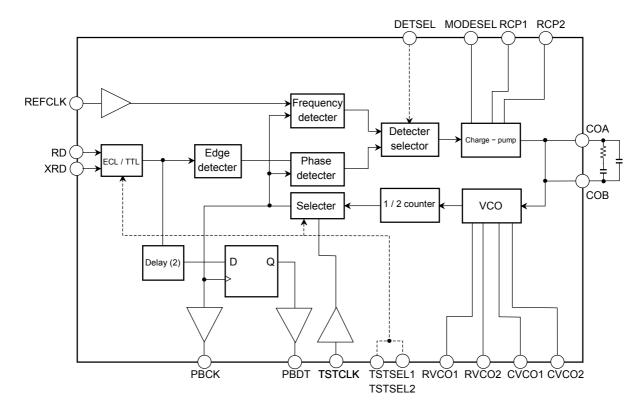
Weight: 0.17g (typ.)

Pin Connectoion

Top view										
NC	1 ()	30	СОВ							
RVCO1	2	29	COA							
AGND2	3	28	AGND1							
CVCO1	4	27	RCP2							
RVCO2	5	26	RCP1							
CVCO2	6	25	AVCC1							
AVCC2	7	24	DETSEL							
TMON1	8	23	TSTCLK							
TMON2	9	22	DVCC3							
XTMON2	10	21	PBDT							
V_TTLO	11	20	PBCK							
MODESEL	12	19	DGND3							
TSTCPMP	13	18	TSTSEL2							
RD	14	17	REFCLK							
XRD	15	16	TSTSEL1							



Block Diagram



Pin Function

14 RD Input terminal of data (normal phase) TTL-in Input terminal of data (reverse phase).	Pin No.	Pin Name	Function	In / Out
2 RCUOT between V _{CC} LCUCH	1	NC	NC terminal. (open at normal use)	_
4CVC01VCO adjusting terminal. Connect a capacitor (C_{VCO}) between this pin and pin65RVC02VCO adjusting terminal. Connect an external resistor (R_{VCO2})-6CVC02VCO adjusting terminal. Connect a capacitor (C_{VCO}) between this pin and pin47AVCC2Analog power supply voltage for VCO8TMON1NC terminal (open at normal use)-9TMON2NC terminal (open at normal use)-10XTMON2NC terminal (open at normal use)-11V_TTLOInput terminal for TTL voh (high voltage level of pin20, and pin21 output) limitting12MODESELInput terminal for switching the normal mode and the serching mode. (H: Normal mode, L: Serching mode)-13TSTCPMPNC terminal of data (normal phase)-14RDInput terminal of data (reverse phase). (this terminal is active when TSTSEL1 = L and TSTSEL2 = H. Otherelse, short with V_{CC} .)(ECL-in of TTL-in16TSTSEL1Input terminal for test mode selecting. (refer the chapter of "test mode")-17REFCLKReference clock input of frequency synchronizer.TTL-in18TSTSEL2Input terminal of data latch clock.TTL-in20PBCKOutput terminal of data latch.TTL-in21PBDTOutput terminal of data latch.TTL-in22DVCC3Digital ground for TTL output23TSTCLKInput terminal of data latch.TTL-out24DETS	2	RVCO1		_
4 DVCO1 pin and pin6. — 5 RVC02 VCO adjusting terminal. Connect an external resistor (R _{VC02}) — 6 CVC02 VCO adjusting terminal. Connect a capacitor (C _{VC0}) between this pin and pin4. — 7 AVCC2 Analog power supply voltage for VCO. — 8 TMON1 NC terminal (open at normal use) — 9 TMON2 NC terminal (open at normal use) — 10 XTMON2 NC terminal for TL voh (high voltage level of pin20, and pin21 output) limitting. — 11 V_TTL0 Input terminal for Switching the normal mode and the serching mode. (H: Normal mode, L: Serching mode) TTL-in 13 TSTCPMP NC terminal. (open at normal use.) — 14 RD Input terminal for switching the normal mode and the serching mode. (H: Normal mode, L: Serching mode) — 15 XRD Input terminal of data (reverse phase). (this terminal is active when TSTSEL1 = L and TSTSEL2 = H. Othereise, short with V _{CC} .) — 16 TSTSEL1 Input terminal for test mode selecting. (refer the chapter of "test mode") — 19 DGND3 Digital ground for TL output. — — 20	3	AGND2	Analog ground for VCO.	_
3 RVC02 between V_{CC}^{-} Ltotal — 6 CVC02 VCO adjusting terminal. Connect a capacitor (CvCO) between this pin and pin4. — 7 AVCC2 Analog power supply voltage for VCO. — 8 TMON1 NC terminal (open at normal use) — 9 TMON2 NC terminal (open at normal use) — 10 XTMON2 NC terminal (open at normal use) — 11 V_TTLO Input terminal for TTL voh (high voltage level of pin20, and pin21 output) limitting. — 12 MODESEL Input terminal for switching the normal mode and the serching mode. (H: Normal mode, L: Serching mode) TTL-in 13 TSTCPMP NC terminal. (open at normal use.) — 14 RD Input terminal of data (normal phase) TTL-in or TTL-in 15 XRD Input terminal of data (reverse phase). (this terminal is active when TSTSEL1 = L and TSTSEL2 = H. (ECL-in) Otherelse, short with V _{CC} .) — 16 TSTSEL1 Input terminal for test mode selecting. (refer the chapter of "test mode") — 17 REFCLK Reference clock input of frequency synchronizer. TTL-in 18 TSTSEL2 <t< td=""><td>4</td><td>CVCO1</td><td></td><td>_</td></t<>	4	CVCO1		_
6 CVC02 pin and pin4. Image: CVC02 pin and pin4. 7 AVCC2 Analog power supply voltage for VCO. — 8 TMON1 NC terminal (open at normal use) — 9 TMON2 NC terminal (open at normal use) — 10 XTMON2 NC terminal (open at normal use) — 11 V_TTLO Input terminal for TTL voh (high voltage level of pin20, and pin21 output) limitting. — 12 MODESEL Input terminal for switching the normal mode and the serching mode. (H: Normal mode, L: Serching mode) TTL-in 13 TSTCPMP NC terminal (open at normal use.) — 14 RD Input terminal of data (reverse phase). (this terminal of data (reverse phase). (this terminal is active when TSTSEL1 = L and TSTSEL2 = H. Otherelse, short with V _{CC} .) (ECL-in) 16 TSTSEL1 Input terminal for test mode selecting. (refer the chapter of "test mode") — 19 DGND3 Digital ground for TL output. — 20 PBCK Output terminal of data latch clock. TTL-int-out 21 PBDT Output terminal of stal latch clock. TTL-int-out 22 DVCC3 Digital power	5	RVCO2		_
8 TMON1 NC terminal (open at normal use) — 9 TMON2 NC terminal (open at normal use) — 10 XTMON2 NC terminal (open at normal use) — 11 V_TTLO Input terminal for TTL voh (high voltage level of pin20, and pin21 output) limiting. — 11 V_TTLO Input terminal for switching the normal mode and the serching mode. — 12 MODESEL Input terminal of akt (normal use.) — 13 TSTCPMP NC terminal. (open at normal use.) — 14 RD Input terminal of data (normal phase) ECL-in or TTL-in 15 XRD Input terminal of data (reverse phase). (this terminal is active when TSTSEL1 = L and TSTSEL2 = H. Otherelse, short with V _{CC} .) [ECL-in) 16 TSTSEL1 Input terminal for test mode selecting. (refer the chapter of "test mode") — 17 REFCLK Reference clock input of frequency synchronizer. TTL-in 18 TSTSEL2 Input terminal of data latch clock. TTL-in 19 DGND3 Digital ground for TTL output. — 20 PBCK Output terminal of data latch clock. TTL-out	6	CVCO2		_
9 TMON2 NC terminal (open at normal use) — 10 XTMON2 NC terminal (open at normal use) — 11 V_TTLO Input terminal for TTL voh (high voltage level of pin20, and pin21 output) limitting. — 12 MODESEL Input terminal for switching the normal mode and the serching mode. (H: Normal mode, L: Serching mode) TTL-in 13 TSTCPMP NC terminal. (open at normal use.) — 14 RD Input terminal of data (normal phase) ECL-in or TTL-in 15 XRD Input terminal of data (reverse phase). (this terminal is active when TSTSEL1 = L and TSTSEL2 = H. Otherelse, short with V _{CC} .) (ECL-in) 16 TSTSEL1 Input terminal for test mode selecting. (refer the chapter of "test mode") — 17 REFCLK Reference clock input of frequency synchronizer. TTL-in 18 TSTSEL2 Input terminal of test mode selecting. (refer the chapter of "test mode") — 19 DGND3 Digital ground for TTL output. — 20 PBCK Output terminal of ata latch. TTL-out 21 PBDT Output terminal of x1 / 2 vco test clock. (short with V _{CC} at mormal use.) — 23	7	AVCC2	Analog power supply voltage for VCO.	_
10 XTMON2 NC terminal (open at normal use) — 11 V_TTLO Input terminal for TTL voh (high voltage level of pin20, and pin21 output) limitting. — 12 MODESEL Input terminal for switching the normal mode and the serching mode. (H: Normal mode, L: Serching mode) TTL-in 13 TSTCPMP NC terminal. (open at normal use.) — 14 RD Input terminal of data (normal phase) ECL-in or TTL-in 15 XRD Input terminal of data (reverse phase). (this terminal is active when TSTSEL1 = L and TSTSEL2 = H. Otherelse, short with V _{CC} .) (ECL-in) 16 TSTSEL1 Input terminal for test mode selecting. (refer the chapter of "test mode") — 17 REFCLK Reference clock input of frequency synchronizer. TTL-in 18 TSTSEL2 Input terminal of data latch clock. TTL-out 19 DGND3 Digital ground for TTL output. — 20 PBCK Output terminal of ata latch. clock. TTL-out 21 PBDT Output terminal of ata latch. TTL-out 22 DVCC3 Digital power supply voltage for TTL output. — 23 TSTCLK Input terminal of switch	8	TMON1	NC terminal (open at normal use)	_
11 V_TTLO Input terminal for TTL voh (high voltage level of pin20, and pin21 output) limitting. — 12 MODESEL Input terminal for switching the normal mode and the serching mode. (H: Normal mode, L: Serching mode) TTL-in 13 TSTCPMP NC terminal. (open at normal use.) — 14 RD Input terminal of data (normal use.) — 14 RD Input terminal of data (reverse phase). (this terminal is active when TSTSEL1 = L and TSTSEL2 = H. Otherelse, short with V _{CC} .) (ECL-in) 16 TSTSEL1 Input terminal for test mode selecting. (refer the chapter of "test mode") — 17 REFCLK Reference clock input of frequency synchronizer. TTL-in 18 TSTSEL2 Input terminal for test mode selecting. (refer the chapter of "test mode") — 17 REFCLK Reference clock input of frequency synchronizer. TTL-in 18 TSTSEL2 Input terminal of data latch clock. TTL-out 20 PBCK Output terminal of data latch clock. TTL-out 21 PBDT Output terminal of data latch clock. TTL-out 22 DVCC3 Digital power supply voltage for TTL output. — 23	9	TMON2	NC terminal (open at normal use)	_
11 V_1LU pin21 output) limitting. Image: Constraint of the second	10	XTMON2	NC terminal (open at normal use)	_
12 INODESEL (H: Normal mode, L: Serching mode) ITL-III 13 TSTCPMP NC terminal. (open at normal use.) — 14 RD Input terminal of data (normal phase) ECL-in or TTL-in 15 XRD Input terminal of data (reverse phase). (this terminal is active when TSTSEL1 = L and TSTSEL2 = H. Otherelse, short with V _{CC} .) (ECL-in) 16 TSTSEL1 Input terminal for test mode selecting. (refer the chapter of "test mode") — 17 REFCLK Reference clock input of frequency synchronizer. TTL-in 18 TSTSEL2 Input terminal for test mode selecting. (refer the chapter of "test mode") — 19 DGND3 Digital ground for TTL output. — 20 PBCK Output terminal of data latch clock. TTL-out 21 PBDT Output terminal of data latch. TTL-out 22 DVCC3 Digital power supply voltage for TTL output. — 23 TSTCLK Input terminal of x1 / 2 vco test clock. (short with V _{CC} at mormal use.) — 24 DETSEL Input terminal for switching the frequency detective mode and the phase detective mode. (L : The frequency detective mode.) TTL-in	11	V_TTLO		_
14RDInput terminal of data (normal phase)ECL-in or TTL-in15XRDInput terminal of data (reverse phase). (this terminal is active when TSTSEL1 = L and TSTSEL2 = H. Otherelse, short with V _{CC} .)(ECL-in)16TSTSEL1Input terminal for test mode selecting. (refer the chapter of "test mode")-17REFCLKReference clock input of frequency synchronizer.TTL-in18TSTSEL2Input terminal for test mode selecting. (refer the chapter of "test mode")-19DGND3Digital ground for TTL output20PBCKOutput terminal of data latch clock.TTL-out21PBDTOutput terminal of data latch.TTL-out22DVCC3Digital power supply voltage for TTL output23TSTCLKInput terminal of ×1 / 2 vco test clock. (short with V _{CC} at mormal use.)-24DETSELInput terminal for switching the frequency detective mode H : The phase detective mode.)TTL-in	12	MODESEL	Input terminal for switching the normal mode and the serching mode. (H: Normal mode, L: Serching mode)	TTL–in
14RDInput terminal of data (normal phase)TTL-in15XRDInput terminal of data (reverse phase). (this terminal is active when TSTSEL1 = L and TSTSEL2 = H. Otherelse, short with V _{CC} .)(ECL-in)16TSTSEL1Input terminal for test mode selecting. (refer the chapter of "test mode")-17REFCLKReference clock input of frequency synchronizer.TTL-in18TSTSEL2Input terminal for test mode selecting. (refer the chapter of "test mode")-19DGND3Digital ground for TTL output20PBCKOutput terminal of data latch clock.TTL-out21PBDTOutput terminal of data latch.TTL-out22DVCC3Digital power supply voltage for TTL output23TSTCLKInput terminal of ×1 / 2 vco test clock. (short with V _{CC} at mormal use.)-24DETSELInput terminal for switching the frequency detective mode H : The phase detective mode.)TTL-in	13	TSTCPMP	NC terminal. (open at normal use.)	_
15XRD(this terminal is active when TSTSEL1 = L and TSTSEL2 = H. Otherelse, short with V _{CC} .)(ECL-in)16TSTSEL1Input terminal for test mode selecting. (refer the chapter of "test mode")—17REFCLKReference clock input of frequency synchronizer.TTL-in18TSTSEL2Input terminal for test mode selecting. (refer the chapter of "test mode")—19DGND3Digital ground for TTL output.—20PBCKOutput terminal of data latch clock.TTL-out21PBDTOutput terminal of data latch.TTL-out22DVCC3Digital power supply voltage for TTL output.—23TSTCLKInput terminal of ×1 / 2 vco test clock. (short with V _{CC} at mormal use.)—24DETSELInput terminal for switching the frequency detective mode H : The phase detective mode.)TTL-in	14	RD	Input terminal of data (normal phase)	ECL-in or TTL-in
17 REFCLK Reference clock input of frequency synchronizer. TTL-in 18 TSTSEL2 Input terminal for test mode selecting. (refer the chapter of "test mode") — 19 DGND3 Digital ground for TTL output. — 20 PBCK Output terminal of data latch clock. TTL-out 21 PBDT Output terminal of data latch. TTL-out 22 DVCC3 Digital power supply voltage for TTL output. — 23 TSTCLK Input terminal of ×1 / 2 vco test clock. (short with V _{CC} at mormal use.) — 24 DETSEL Input terminal for switching the frequency detective mode and the phase detective mode. H : The phase detective mode.) TTL-in	15	XRD	(this terminal is active when TSTSEL1 = L and TSTSEL2 = H.	(ECL-in)
18 TSTSEL2 Input terminal for test mode selecting. (refer the chapter of "test mode") — 19 DGND3 Digital ground for TTL output. — 20 PBCK Output terminal of data latch clock. TTL-out 21 PBDT Output terminal of data latch. TTL-out 22 DVCC3 Digital power supply voltage for TTL output. — 23 TSTCLK Input terminal of ×1 / 2 vco test clock. (short with V _{CC} at mormal use.) — 24 DETSEL Input terminal for switching the frequency detective mode and the phase detective mode. H : The phase detective mode.) TTL-in	16	TSTSEL1	Input terminal for test mode selecting. (refer the chapter of "test mode")	_
19 DGND3 Digital ground for TTL output. — 20 PBCK Output terminal of data latch clock. TTL-out 21 PBDT Output terminal of data latch. TTL-out 22 DVCC3 Digital power supply voltage for TTL output. — 23 TSTCLK Input terminal of ×1 / 2 vco test clock. (short with V _{CC} at mormal use.) — 24 DETSEL Input terminal for switching the frequency detective mode and the phase detective mode. (L : The frequency detective mode H : The phase detective mode.) TTL-in	17	REFCLK	Reference clock input of frequency synchronizer.	TTL–in
20 PBCK Output terminal of data latch clock. TTL-out 21 PBDT Output terminal of data latch. TTL-out 22 DVCC3 Digital power supply voltage for TTL output. — 23 TSTCLK Input terminal of ×1 / 2 vco test clock. (short with V _{CC} at mormal use.) — 24 DETSEL Input terminal for switching the frequency detective mode and the phase detective mode. H : The phase detective mode.) TTL-in	18	TSTSEL2	Input terminal for test mode selecting. (refer the chapter of "test mode")	_
21 PBDT Output terminal of data latch. TTL-out 22 DVCC3 Digital power supply voltage for TTL output. — 23 TSTCLK Input terminal of ×1 / 2 vco test clock. (short with V _{CC} at mormal use.) — 24 DETSEL Input terminal for switching the frequency detective mode and the phase detective mode. (L : The frequency detective mode.) TTL-in	19	DGND3	Digital ground for TTL output.	_
22 DVCC3 Digital power supply voltage for TTL output. — 23 TSTCLK Input terminal of ×1 / 2 vco test clock. (short with V _{CC} at mormal use.) — 24 DETSEL Input terminal for switching the frequency detective mode and the phase detective mode. (L : The frequency detective mode.) TTL-in	20	PBCK	Output terminal of data latch clock.	TTL-out
23 TSTCLK Input terminal of ×1 / 2 vco test clock. (short with V _{CC} at mormal use.) — 24 DETSEL Input terminal for switching the frequency detective mode and the phase detective mode. (L : The frequency detective mode H : The phase detective mode.) TTL-in	21	PBDT	Output terminal of data latch.	TTL-out
23 ISTCLK (short with V _{CC} at mormal use.) — 24 DETSEL Input terminal for switching the frequency detective mode and the phase detective mode. (L : The frequency detective mode.) TTL-in	22	DVCC3	Digital power supply voltage for TTL output.	_
24 DETSEL detective mode. (L : The frequency detective mode H : The phase detective mode.) TTL-in	23	TSTCLK		_
25 AVCC1 Analog power supply voltage. —	24	DETSEL	detective mode. (L : The frequency detective mode	TTL–in
	25	AVCC1	Analog power supply voltage.	_

<u>TOSHIBA</u>

Pin No.	Pin Name	Function	In / Out
26	RCP1	Adjusting terminal of charge pump at normal mode. Connect an external resistor (R _{cp1}) between GND.	_
27	RCP2	Adjusting terminal of charge pump at normal mode. Connect an external resistor (R _{cp2}) between GND.	_
28	AGND1	Analog ground	Ι
29	COA	Connecting terminal of loop filter. Connect an external loop filter between this pin and 30pin.	_
30	СОВ	Connecting terminal of loop filter. Connect an external loop filter between this pin and 29pin.	—

Absolute Maximum Rating (Ta = 27°C)

Parameter	Symbol	Rating	Unit
Supply voltage	AVCC	7	V
Input voltage	V _{IN}	$-0.3 \sim V_{CC} + 0.3$	V
Output voltage	V _{OUT}	$-0.3 \sim V_{CC} + 0.3$	V
Storage temperature	T _{stg}	-55~150	°C

Recommended Operating Condition

Parameter	Symbol	Condition	Min.	Тур.	Max.	Unit
Supply voltage	AVCC	—	4.5	5	5.5	V
Operation temperature	T _{opr}	_	-5		75	°C

Power Supply (unless otherwise specifide, $Ta = 27^{\circ}C$, $V_{CC} = 5.0V$)

Parameter	Symbol	Condition	Min.	Тур.	Max.	Unit
Supply current	IPLCC	TSTSEL1 = H, TSTSEL2 = L DETSEL = L, MODSEL = H			65	mA

Electrical Characteristic (unless otherwise specified, Ta = 27°C, V_{CC} = 5.0V)

Parameter	Symbol	Test Circuit	Test Condition	Min.	Тур.	Max.	Unit
High level input voltage (1)	V _{IH}	—	TTL input pins	2.0	—	—	V
Low level input voltage (1)	V _{IL}	_	TTL input pins	_	—	0.4	V
High level input current (1)	IIH	_	TTL input pins	_	—	20	μA
Low level input current (1)	١ _{١L}	_	TTL input pins	—	—	-360	μA
High level input voltage (2)	VIHE	_	ECL input pins	V _{CC} -1.0	_	_	V
Low level input voltage (2)	VILE	_	ECL input pins	-	_	V _{CC} -1.5	V
High level input current (2)	IIHE	—	ECL input pins	_	—	2.0	mA
Low level input current (2)	IILE	_	ECL input pins	—	—	1.6	mA
High level output voltage (1)	V _{OH}	_	TTL output pins I _{OH} = 400μA	VTTLO –0.2		VTTLO +0.2	V
Low level output voltage (1)	V _{OL}	_	TTL output pins I _{OL} = 4mA	-	_	1.0	V
Output rise time (1)	TOR	_	TTL output pins 1.5V to 3.5V $C_L \leq 30pF$ *	1 —	_	5	ns
Output fall time (1)	TOF	_	TTL output pins 3.5V to 1.5V CL \leq 30pF *	1 —	_	5	ns
Input voltage range to VTTLO terminal	VTTLO	_		2.7	_	3.3	V

*1; Design guaranteed value.

Charge Pump (unless otherwise specified, $Ta = 27^{\circ}C$, $V_{CC} = 5.0V$)

Parameter	Symbol	Test Circuit	Test Circuit Condition		Min.	Тур.	Max.	Unit	
	lan	_	At normal mode *	'1	30	-	_		
Range of output current setting	I _{CP}	_	At serching mode *2	2	—	-	800	μA	
Accuracy of output current	l _{acu}		At normal mode		-6	Ι	+6	%	
setting		_	At serching mode		-8	-	+8	70	
Leak current I _{rea}			Between COA pin and COB pin, at high impedance		-3.5		+3.5	μA	

*1; Output current is set by an external resistor (R_{cp1}), as following;

2×1.3 / R_{cp1} = (output current at normal mode).

*2; Output current is set by external resisters (R_{cp1}, R_{cp2}), as following; 2×1.3 / R_{cp1}+8×1.3 / R_{cp2} = (output current at search mode).

(Note) The above values are all at open loop.

VCO (unless otherwise specified, Ta = 27° C, V_{CC} = 5.0V)

Parameter	Symbol	Test Circuit	Condition	Min.	Тур.	Max.	Unit
Input voltage of VCO (V (COB –COA))	Vvco	_	$\label{eq:RVC01} \begin{array}{l} R_{VC01} = 3.75 \ k\Omega \\ R_{VC02} = 1.21 \ k\Omega \\ C_{VC0} = 39 p F \\ f_{VC0} = 28.224 \text{MHz} \end{array} \hspace{1.5cm} ^{*1}$	0.25		0.45	V
Upper limitation of VCO frequency	f _{max}	_	$\label{eq:relation} \begin{array}{l} R_{VCO1} = 3.75 \ k\Omega \\ R_{VCO2} = 1.21 \ k\Omega \\ C_{VCO} = 39 \text{pF} \\ \text{V} \ (\text{COB} - \text{COA}) = 0.6 \text{V} \end{array} \qquad $	29.5			MHz
Lower limitation of VCO frequency	f _{min}	_	$R_{VCO1} = 3.75 kΩ$ $R_{VCO2} = 1.21 kΩ$ $C_{VCO} = 39pF$ *1 V (COB -COA) = -0.6V			23.5	MHz
Control gain (F / V)	G _{VCO}	_	R_{VCO1} = 3.75 kΩ R_{VCO2} = 1.21 kΩ C_{VCO} = 39pF *1 Voltage (COB –COA) Excursion 0.3V to –0.3V	6		7.7	MHz / V
VCO jitter	tjit	_	PBCK pin at ×3 transfer rate *2		300		ps

*1; C_{VCO} inclides the package capacitance.

*2; Design guaranteed value.

(Note) The above values are all at open loop, measured at the PBCK pin

Closed Loop (unless otherwise specified, $Ta = 27^{\circ}C$, $V_{CC} = 5.0V$)

Parameter	Symbol	Test Circuit	Condition		Тур.	Max.	Unit
VCO jitter in closed loop	^t jit2N	_	In search mode lock to REFCLK			0.5	ns
VCO jitter in closed loop	t _{jit2S}		In normal mode lock to RD			0.4	ns

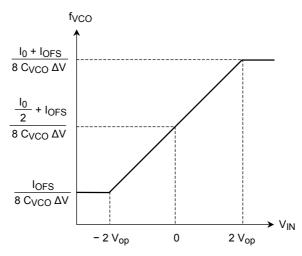
Values of external parts are (R_{VCO1} = 3.75 k Ω , R_{VCO2} = 1.21 k Ω , C_{VCO} = 39pF (including storage capacitor), R_{CP1} = 8.25k, R_{CP2} = 30.1k).

Character Of VCO

The connection of input voltage and output frequency of VCO (measured at PBCK after the $1\,/\,2$ frequency counter) is written as following;

$$f_{vco} = \begin{cases} \frac{1}{8 \cdot C_{vco} \cdot \Delta V} \cdot (I_O + I_{ofs}) & (V_{in} > 2V_{op}) \\\\ \frac{1}{8 \cdot C_{vco} \cdot \Delta V} (\frac{I_O}{4V_{op}} \cdot V_{in} + \frac{I_O}{2} + I_{ofs}) & (2V_{op} > V_{in} > -2V_{op}) \\\\ \frac{1}{8 \cdot C_{vco} \cdot \Delta V} \cdot I_{ofs} & (V_{in} < -2V_{op}) \end{cases}$$

Where; C_{vco} is an external capacitor between 4pin and 6pin, $\Delta V = 0.35V$, $V_{op} = 0.275V$, V_{in} is the input voltage of VCO (differential), $I_O = 3 \times 1.3 / R_{vco1}$, and $l_{ofs} = 2 \times 1.3 / R_{vco2}$.



So, the gain of VCO is defined as following (at PBCK); $% \left(\left({{{\rm{A}}_{{\rm{B}}}} \right) \right) = \left({{{\rm{A}}_{{\rm{B}}}} \right)$

$$\frac{1}{8 \cdot C_{\text{VCO}} \cdot \Delta \text{V}} \cdot \frac{\text{I}_{\text{O}}}{4 \text{V}_{\text{OP}}}$$

And, upper limitation f upper, and lower limitation of VCO frequency f lower is defined as follows;

 $f_{upper} = (I_O + I_{ofs}) / 8C_{vco} \Delta V$

 $f_{lower} = I_{ofs} / 8C_{vco} \Delta V$

I 0 can be determined by selecting R_{vco1} , and I ofs can by R_{vco2} . So, you can independently determine the gain of VCO, upper limitation and lower limitation of VCO frequency by selecting C_{vco} , R_{vco1} , and R_{vco2} .

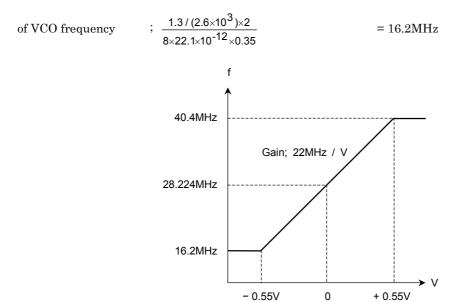
[Example] When, $C_{vco} = 22.1 \text{pF}$, $R_{vco1} = 2.6 \text{k}\Omega$, $R_{vco2} = 2.6 \text{k}\Omega$,

Gain of VCO ;
$$\frac{1.3 / (2.6 \times 10^3) \times 3}{8 \times 22.1 \times 10^{-12} \times 0.35 \times 4 \times 0.275}$$
 = 22MHz / V

Upper limitation

of VCO frequency ;
$$\frac{1.3 / (2.6 \times 10^3) \times 3 + 1.3 / (2.6 \times 10^3) \times 2}{8 \times 22.1 \times 10^{-12} \times 0.35} = 40.4 \text{MHz}$$

Lower limitation



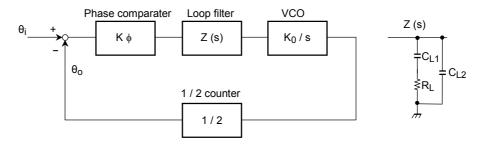
Function Description:

The angular frequency (ω_n) and dumping facter (ζ) are adjusted by external devices. The setting procedure is shown as following.

The setting conditions to lock PLL inside a constant time;

- Data transfer rate: 28.224 Mbps (f_M = 28.244 MHz)
- The capturing signal of PLL: The rectangle wave of 14.112MHz (data pattern is 101010...),
- The term of this data is continuous 180 bits. • The capturing time of PLL: 1 / (14.114×10⁶) ×180 = 12.75×10⁻⁶s
 - The capturing time of PLL: $1 / (14.114 \times 10^6) \times 180 = 12.75 \times 10^{-6}$ s $12.75 \times 10^{-6} \times 0.9 = 11.5$ µs (this 0.9 is a factor of margin.)

[The transfer function of PLL]



The transfer function (F (S)), the angular frequency (ω_n), and the dumping facter (ζ) of the above composition are defined as following (However C_{L2} is ignored as $C_{L2} \ll C_{L1}$):

$$\omega_{n} = \left(\frac{K}{C_{L1}}\right)1/2$$
$$\zeta = \frac{R_{L}C_{L1}\omega_{n}}{2}$$

[Calculation of ζ]

The dumping factor (ζ) is set to 0.7 as the most stable response characteristic. Besides $\omega_n\,t$ is assumed to set as 6.

[Calculation of ω_n]

The capturing time of PLL is expected as above 11.5µs. Therefore (ω_n) is determinated as the following: $\omega_n = 6 / (11.5 \times 10^{-6}) = 552 \text{krad} / \text{s}$

[Calculation of K₀ (VCO control gain)]

K₀ is determined as the following; K₀ = 40MHz / V = 251.3Mrad / V

[Calculation of Kø (phase detector gain)]

K ϕ is estimated as the following (the current of charge pump is set as $\pm 50 \mu A.)$

$$K\phi = \frac{1}{2} \cdot \frac{1}{2\pi} \times 50 \times 10^{-6} = 3.98 \times 10^{-6} (A / rad)$$

The current of charge pump (Ichp) is set by an external resister (R_{cp1}), connected with R_{cp1} (26pin). When "H"level voltage inputs to MODESEL (12pin), Ichp is set as the following:

$$\begin{split} I_{chp} = 2\times1.3 \ / \ R_{CP1} \rightarrow R_{CP1} = 2\times1.3 \ / \ I_{chp} = 2\times1.3 \ / \ 50\times10^{-6} = 52\times10^{3}\Omega \\ Therefore, \ when \ R_{CP1} \ is \ 52k\Omega, \ I_{chp} \ is \ set \ as \ \pm50\mu A \end{split}$$

[Calculation of external devices of loop-filter]

$$C_{L1} = \frac{K\phi \times K_0}{2\omega_n} = \frac{3.98 \times 10^{-6} \times 251.3 \times 10^{6}}{2 \times (522 \times 10^3)^2} = 1800 \times 10^{-6} \text{F}$$

$$\mathsf{R}_L = \frac{2\zeta}{C_{L1} \, ^{(0)}n} = \frac{2 \times 0.7}{1800 \times 10^{-12} \times 522 \times 10^3} = 1.5 \times 10^3 \, \Omega$$

 $C_{L2} = C_{L1} / 10 = 180 pF$

Modesel Switching Function

The TA8552AFN has a function to correspond with the high–speed serching mode of DAT streamer. In the searching mode, the data transfer rate will shift with small percentage error. The TA8552AFN is available to solve this problem by extending the lock–in–range ($\Delta\omega_L$). In the serching mode the current of charge pump will be increased to raise the phase detecter gain, then the lock–in–range ($\Delta\omega_L$) will extend.

This function is selected by modesel (12pin).

(H: Normal mode / L: Searching mode)

[Calculation of the charge pump's current in the searching mode]

The charge pump's current in the searching mode is estimated as the following (the shift rateX of data, transfer is assumed as X = 7% in this example);

 $I_{chp} = \frac{f_M \times X \times 2\pi}{R \times K_0} \times 8\pi = \frac{28.224 \times 10^6 \times 0.07 \times 2 \times 3.14}{1.5 \times 10^3 \times 251.3 \times 10^6} \times 8 \times 3.14 = 830 \times 10^{-6} \text{(A)}$

When "L" level voltage inputs to modesel (12pin), the charge pump's current (Ichp) increases. In the normal mode, the charge pump's current (I_{cp1}) is set by an external resister (R_{cp1}). And in the searching mode, another current (I_{cp2}), is set by an external resister (R_{cp2}), adds to Icp1. This (R_{cp2}) is the resister to be connected with RCP2 (27pin)

The additional current $(\mathrm{I}_{\mathrm{Cp2}})$ is determined by the following:

 I_{cp2} = 8×1.3 / R_{cp2}

Therefore, $R_{\mbox{cp2}}$ is estimated as the following:

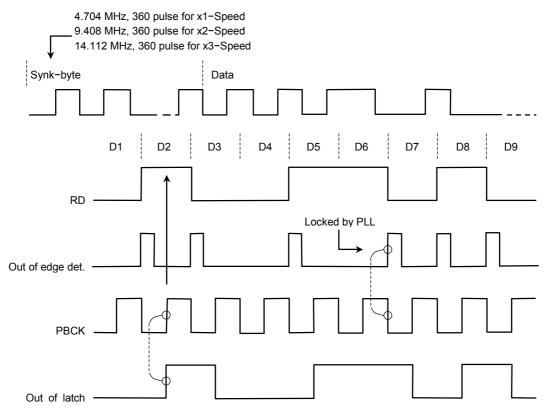
$$R_{cp2} = \frac{8 \times 1.3}{830 \times 10^{-6} \cdot 50 \times 10^{-6}} = 13.3 \times 10^{3} \Omega$$

Modesel function is summarized by the followings

Mode	Normal Mode	High–speed Searghing Mode
Modesel (12pin)	н	L
Charge pump current Ichp	I _{cp1}	I _{cp1} +I _{cp2}
Setting definition	2×1.3 / R _{cp1}	2×1.3 / R _{cp1} +8×1.3 / R _{cp2}

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Timing Chart Of Latch



(Note) Test Monitor Output Terminal

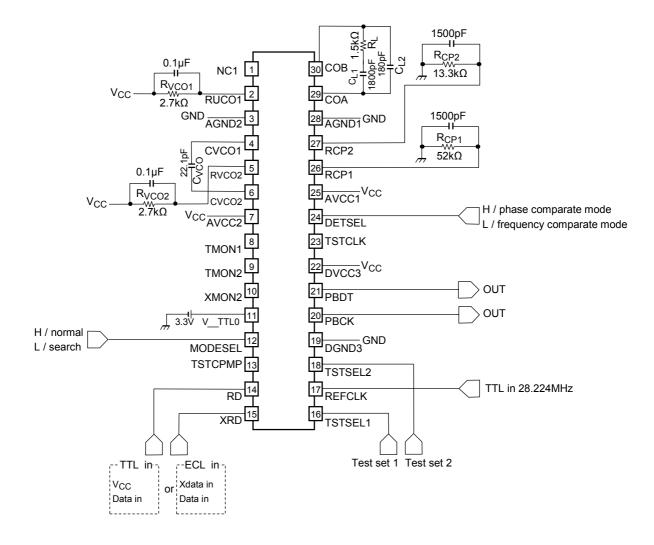
Tst	tsel	Datainput	Function
1	2	Dataniput	T Unction
L	L	TTL input from 14pin (RD)	—
Н	L	TTL input from 14pin (RD)	PBCK (20pin) & PBDT (21pin) becomes disable
L	Н	ECL input from 14pin (RD) and 15pin (XRD)	—
Н	Н	TTL input from 14pin (RD)	The internal PLL becomes disable, and the external clock from tstclk (23pin) becomes enable as input data signal.

(Note) • We commend the use of this IC under the comdition of ECL input from 14pin (RD) and 15pin (XRD) when (TSTSEL1, TSTSEL2) = (L, H)

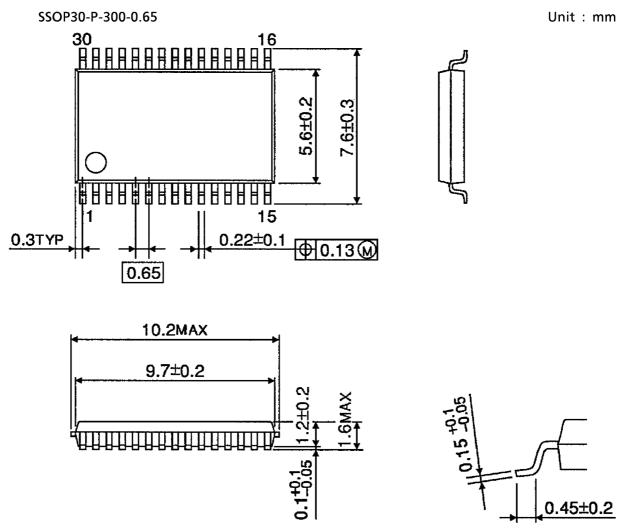
• It is possible of the use of TTL input from 14pin (RD) when (TSTSEL1, TSTSEL2) = (L, L)

Application Diagram

When the data transfer rate is 28.224 Mbps, the application diagram is shown below.



Package Dimensions



Weight: 0.17g (typ.)

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